

Development of a combined TR/DR emittance station for future linear colliders such as CLIC or ILC at ATF2

R. Ainsworth¹, A. Aryshev², T. Aumeyr¹, L.M. Bobb^{1,3},
B. Bolzon^{3,4,5}, E. Bravin³, P. Karataev¹, K. Kruchinin¹, T.
Lefevre³, S. Mazzoni³, M. Shevelev², N. Terunuma², J.
Urakawa²

1. John Adams Institute at Royal Holloway, Egham, Surrey, UK
2. KEK, Ibaraki, Japan
3. CERN European Organisation for Nuclear Research, Geneva, Switzerland
4. Cockcroft Institute, Warrington, Cheshire, UK
5. University of Liverpool, Liverpool, Merseyside, UK



Evolution of technology

OTR

- Widely used (~30 yrs)
- Simple & robust
- Single shot 2D profile
- **But invasive**

OTR PSF

- 2 dimensions
- **2007 - now**
- **Sub- μm resolution**

TR/DR diagnostics @ATF2

- **High-resolution** measurement system for **high-intensity** beams without using a LW
- TR \rightarrow < 100 nm
- DR \rightarrow few μm
- More operational measurement
- Low cost

ODR

- Non-invasive
- Many experiments:
FLASH@DESY [1],
APS@ANL [2],
ATF2@KEK [3]
- **2000 - 2007**
- **14 μm resolution**

UV/X-Ray DR

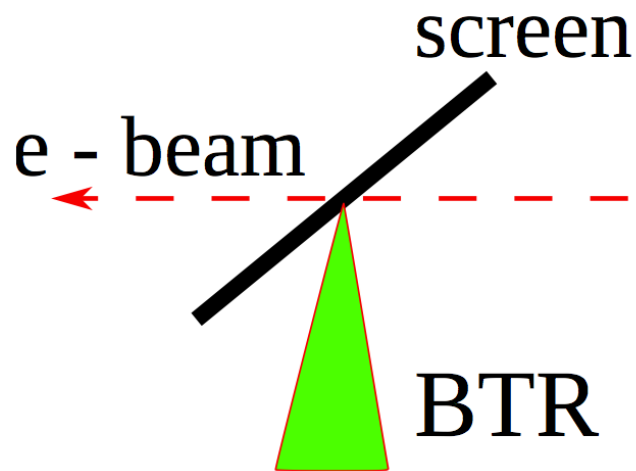
- CsrTA
- Reduce resolution
- **2010 - now**

[1] E. Chiadroni, et al., Proc. of PAC07, Albuquerque, NM, USA, FRPMN027.

[2] A.H. Lumpkin, et al., Phys. Rev. ST Accel. Beams 10, 022802 (2007).

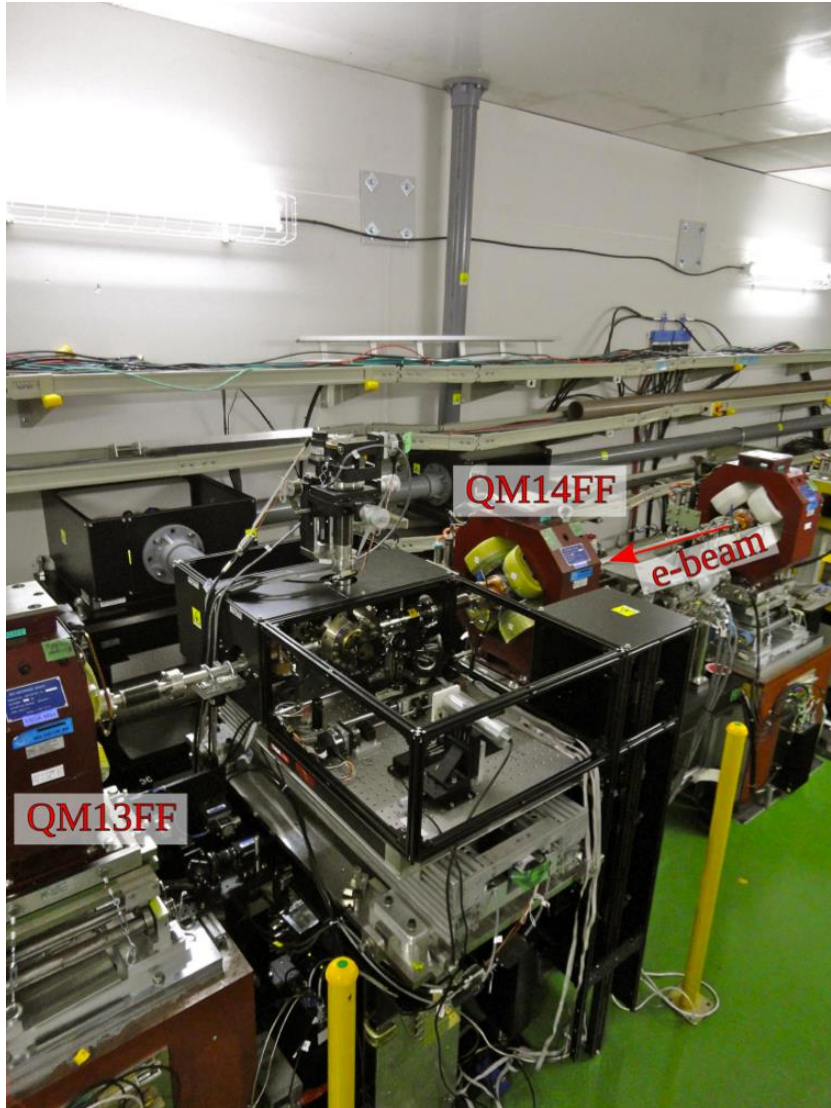
[3] P. Karataev, et al., Phys. Rev. Lett. 93, 244802 (2004)

Transition Radiation

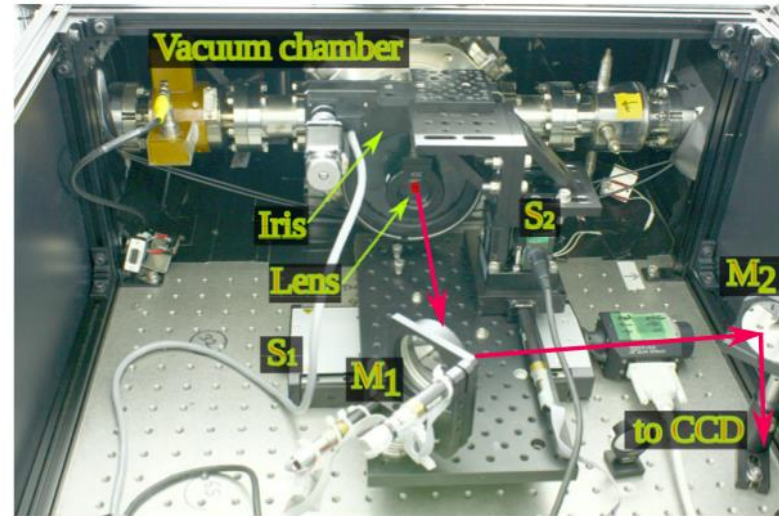
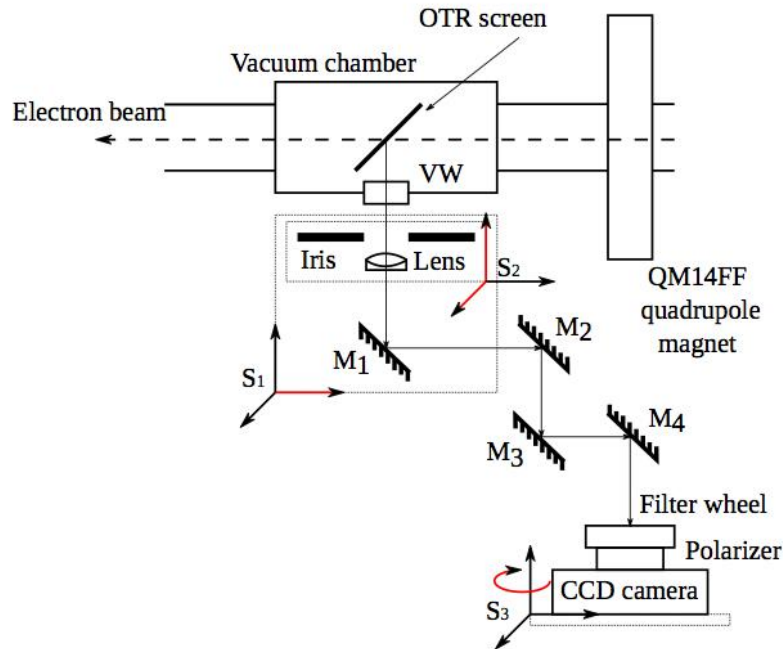


- Transition radiation (TR) appears when a charged particle crosses a boundary between two media with different dielectric constants.
- The resolution is determined by the source dimensions induced by a single particle plus distortion caused by the optical system (diffraction of OTR tails)

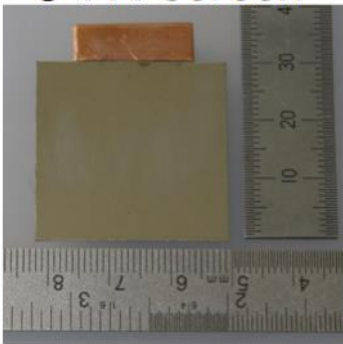
OTR monitor at the ATF2 Extraction Line (former LW system)



Experimental Setup



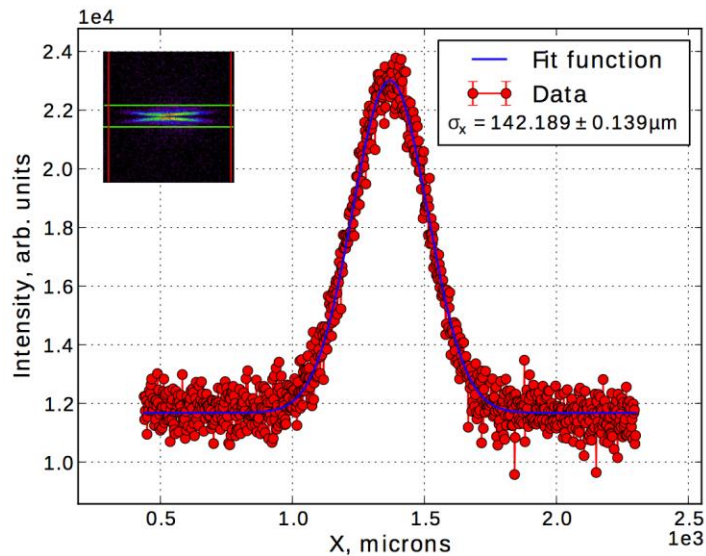
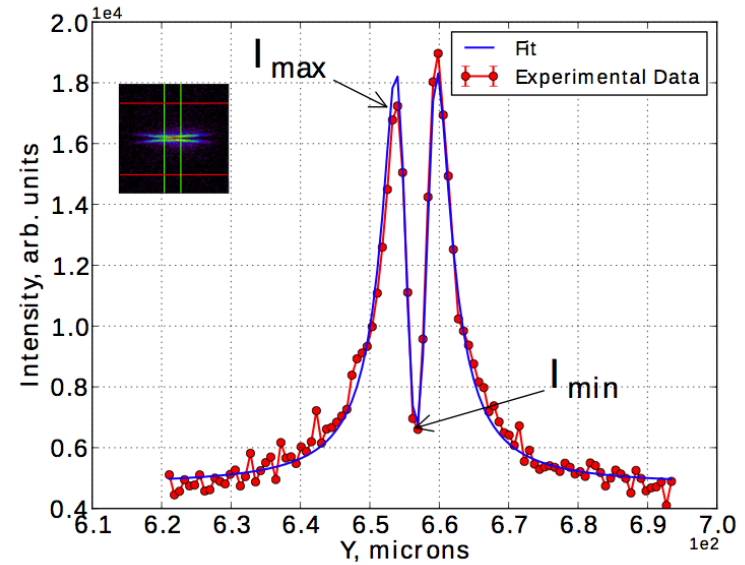
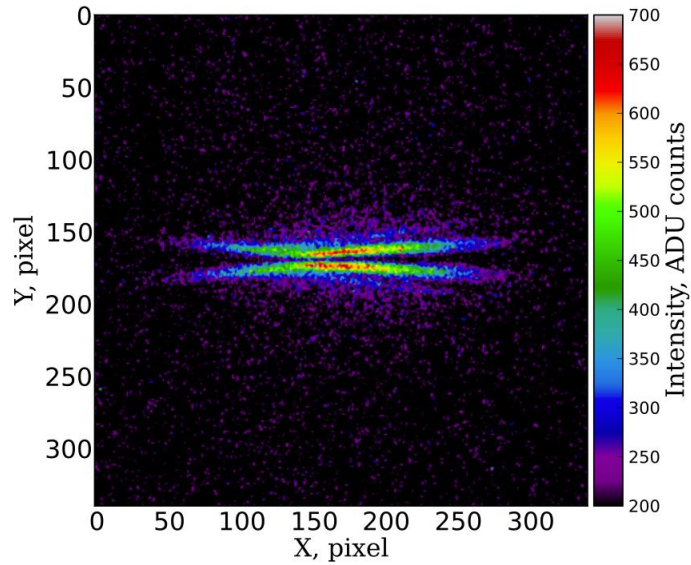
OTR screen



0.3×30×30 mm aluminized silicon

- Lens - "CVI Laser Optics" cemented achromat, $f=120\text{mm}$, $\phi=30\text{mm}$
- CCD Camera - SBIG-ST8300M with $5.4\ \mu\text{m}$ pixel size, 3352×2532 pixel array and $\sim 50\%$ quantum efficiency

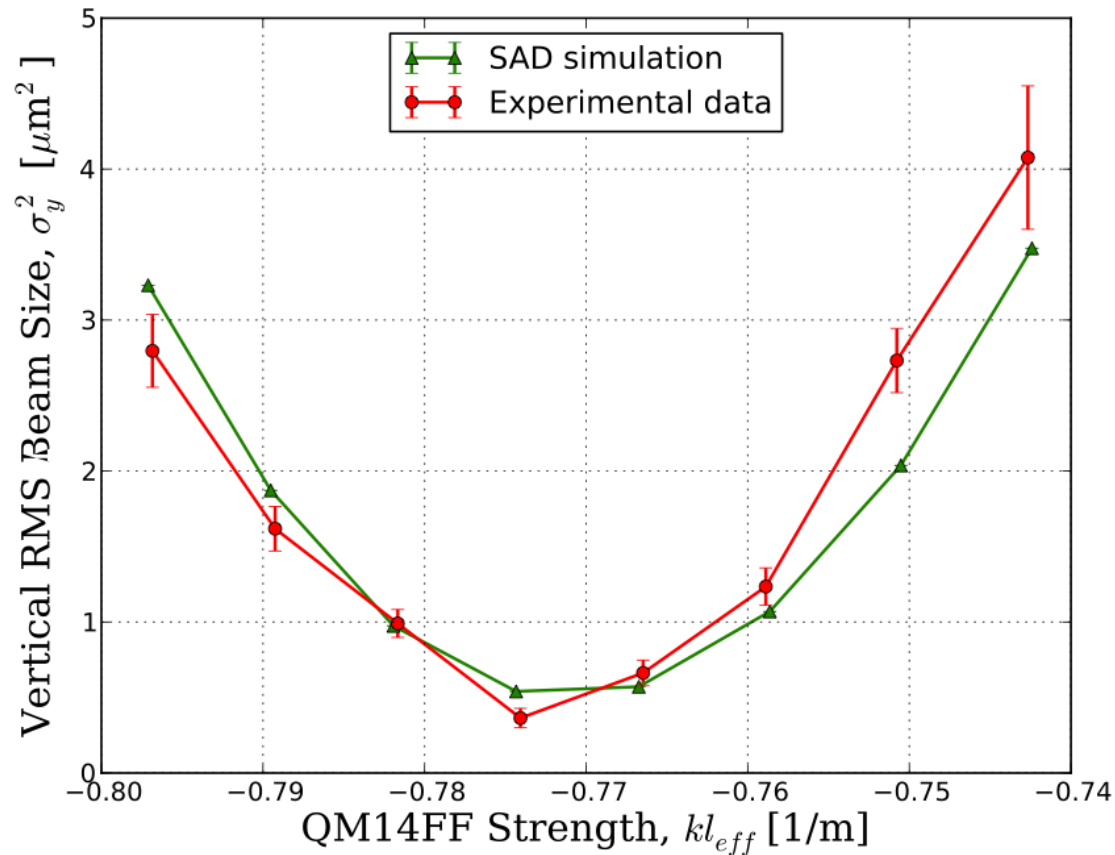
OTR Image and Projections



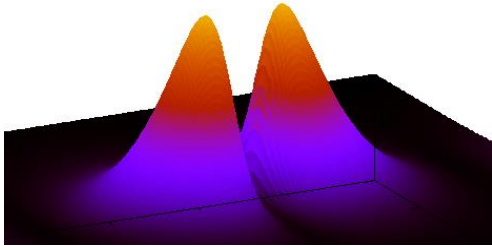
- H size: Gaussian fit
- V size: PSF-like fit function
- Achieved with self-calibration procedure → Rob Ainsworth's talk

Achievement 2013 – quadrupole scan

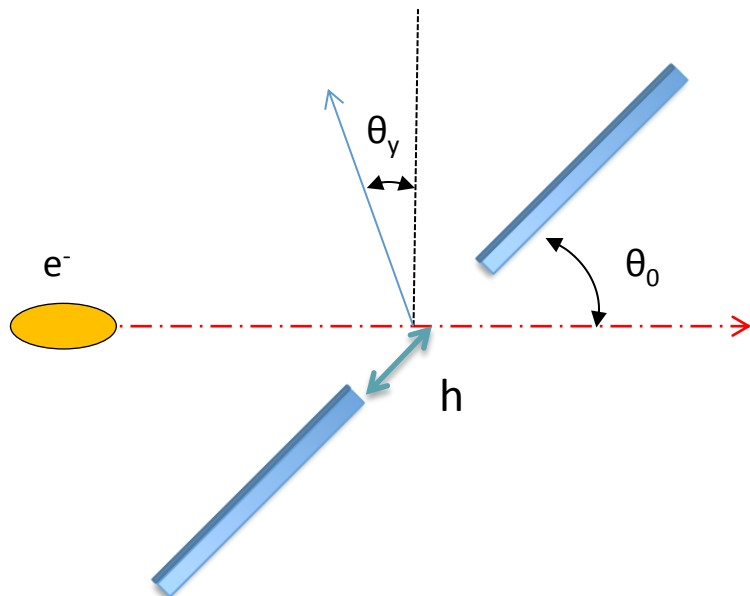
Minimum measured beam size was: $0.754 \pm 0.034 \mu\text{m}$



Diffraction Radiation



DR Angular distribution



Principle:

1. Electron bunch moves through a high precision co-planar slit in a conducting screen (Si + Al coating).
2. Electric field of the electron bunch polarizes atoms of the screen surface.
3. DR is emitted in two directions:
 - along the particle trajectory “Forward Diffraction Radiation” (FDR)
 - In the direction of specular reflection “Backward Diffraction Radiation” (BDR)

Impact parameter:

$$h \leq \frac{\gamma\lambda}{2\pi}$$

Generally:

DR intensity \uparrow as slit size \downarrow

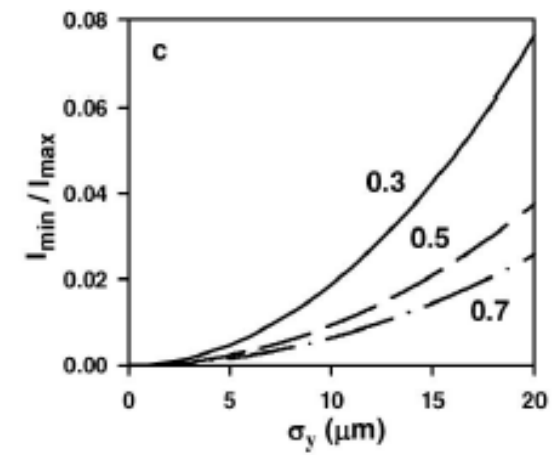
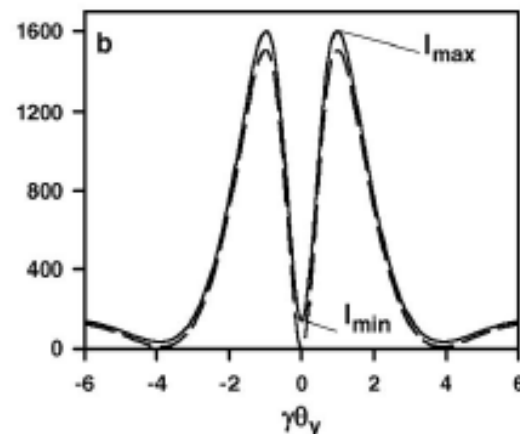
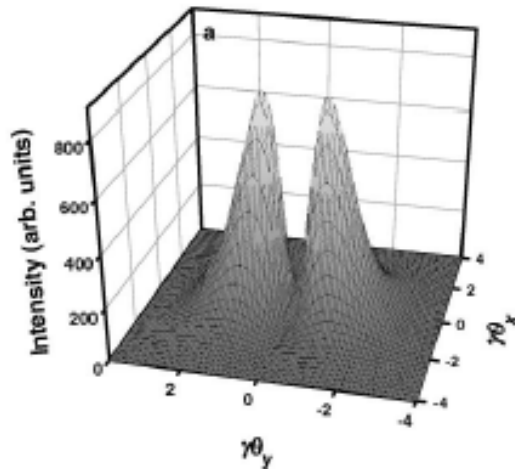
Vertical Beam Size Measurement using the Optical Diffraction Radiation (ODR) model + Projected Vertical Polarisation Component (PVPC)

P. Karataev et al.

PRL 93, 244802 (2004)

PHYSICAL REVIEW LETTERS

week ending
10 DECEMBER 2004



Vertical polarisation component of 3-dimensional (θ_x, θ_y , Intensity) DR angular distribution.

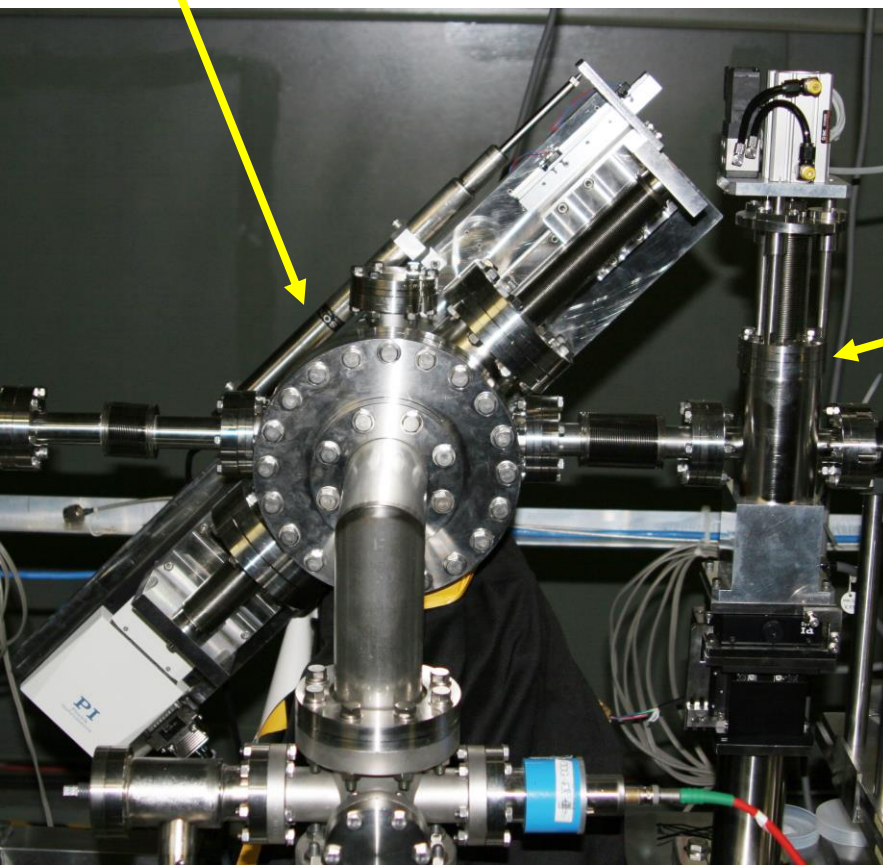
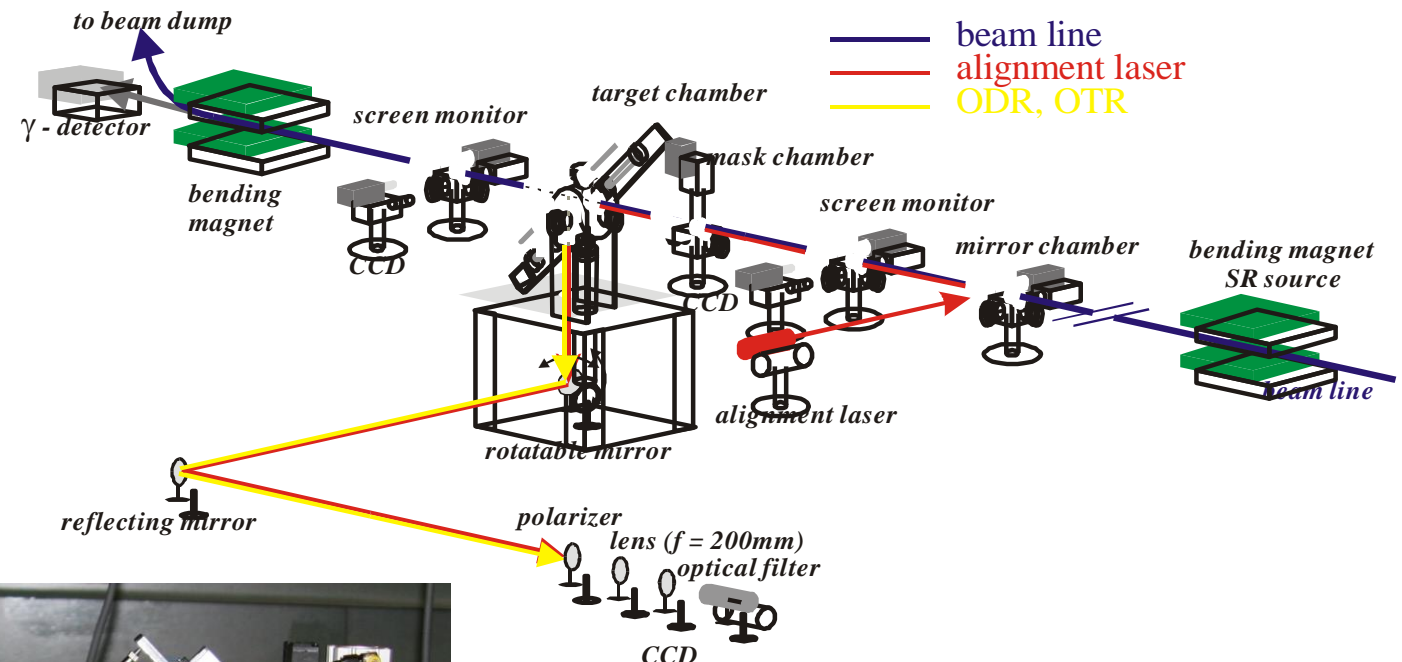


PVPC is obtained by integrating over θ_x to collect more photons.

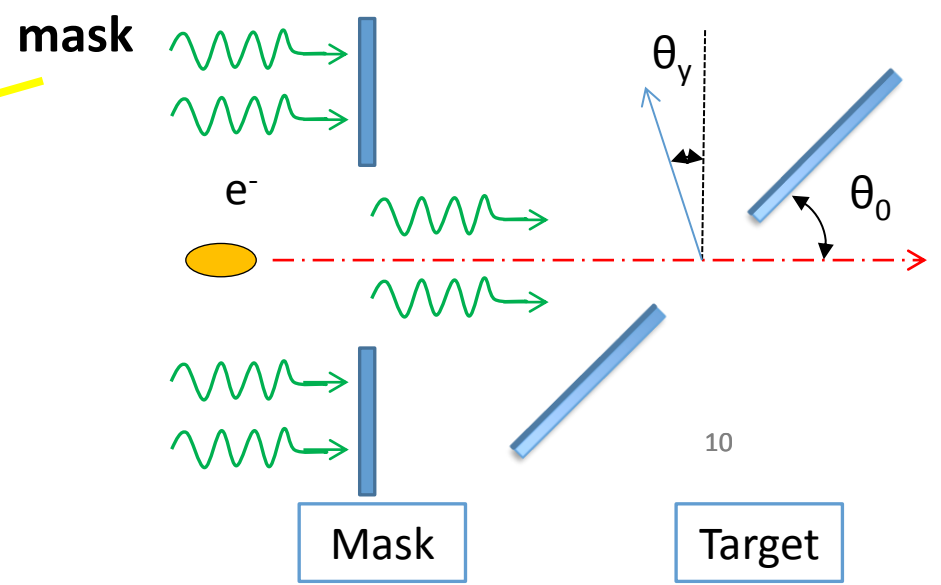


Visibility (I_{min}/I_{max}) of the PVPC is sensitive to vertical beam size σ_y .

target chamber
(at 45° to beam trajectory)

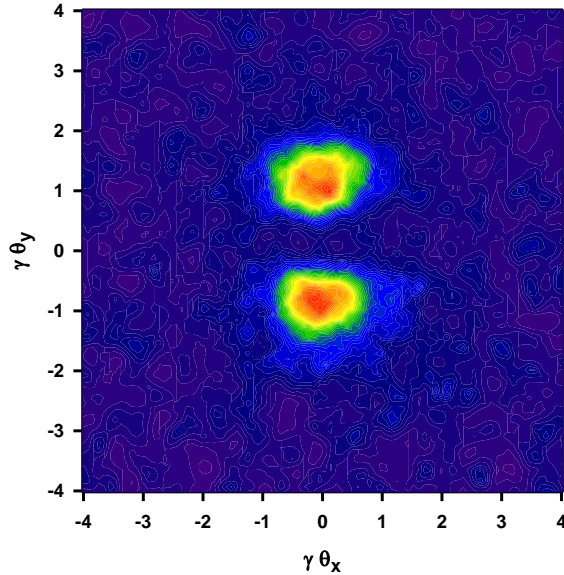


Use a mask upstream of target to suppress SR contribution.

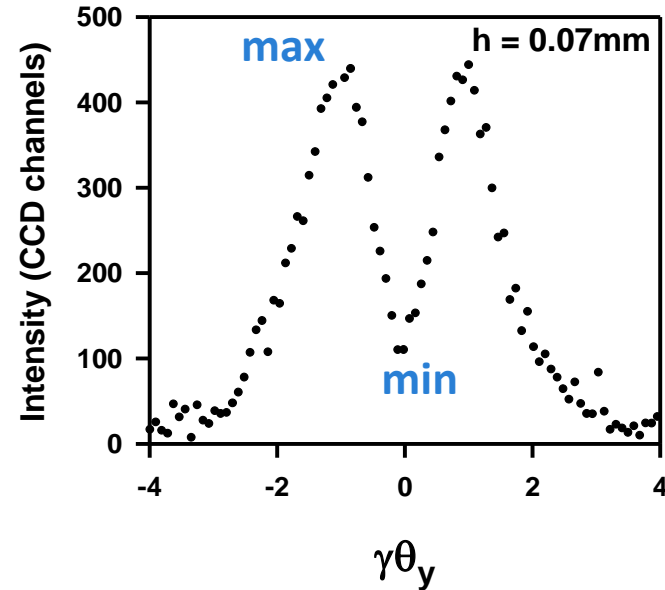


Beam size measurements using ODR

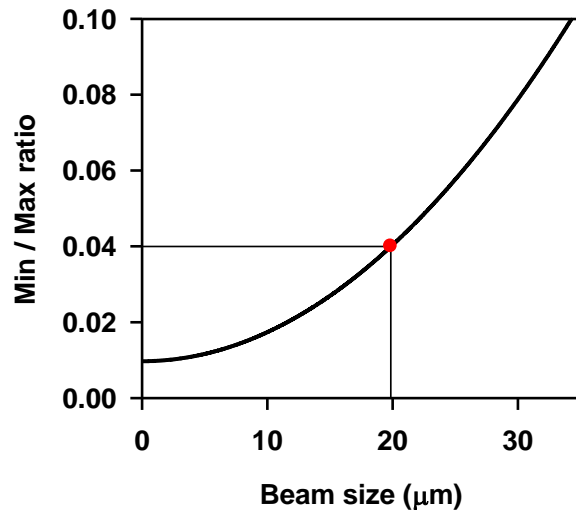
Typical CCD image of ODR vertical polarization component



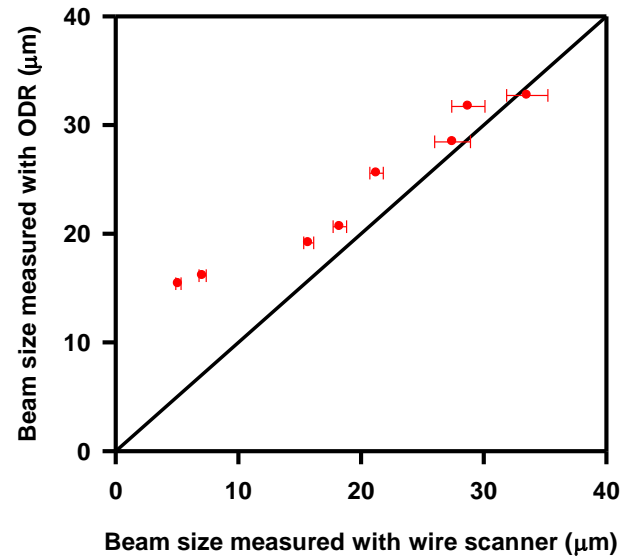
Beam size was changed by a quadrupole magnet

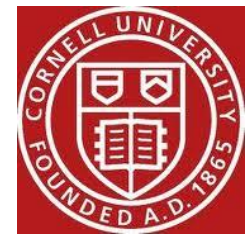


Calibration curve



Measured minimum beam size:
 $\sigma_y = 14 \mu\text{m}$





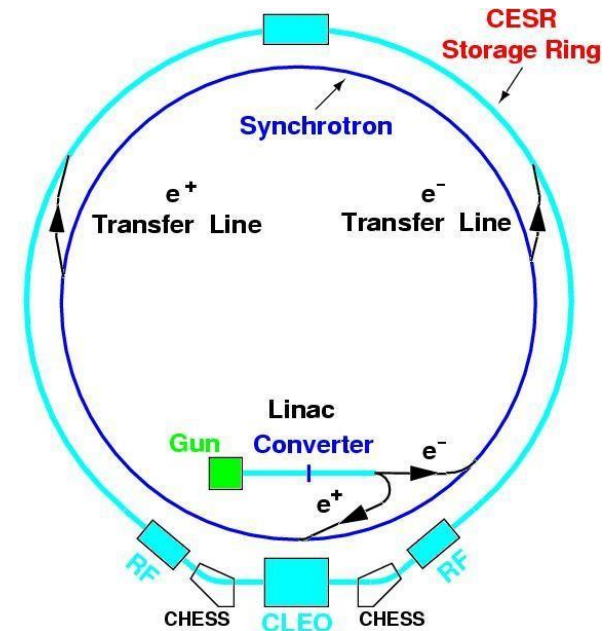
ODR experiment at CEsrTA

Project aim:

To design and test an instrument to measure on the micron-scale the transverse (vertical) beam size for the Compact Linear Collider (CLIC) using incoherent Diffraction Radiation (DR) at UV/soft X-ray wavelengths.

Cornell Electron Storage Ring Test Accelerator (CesrTA) beam parameters:

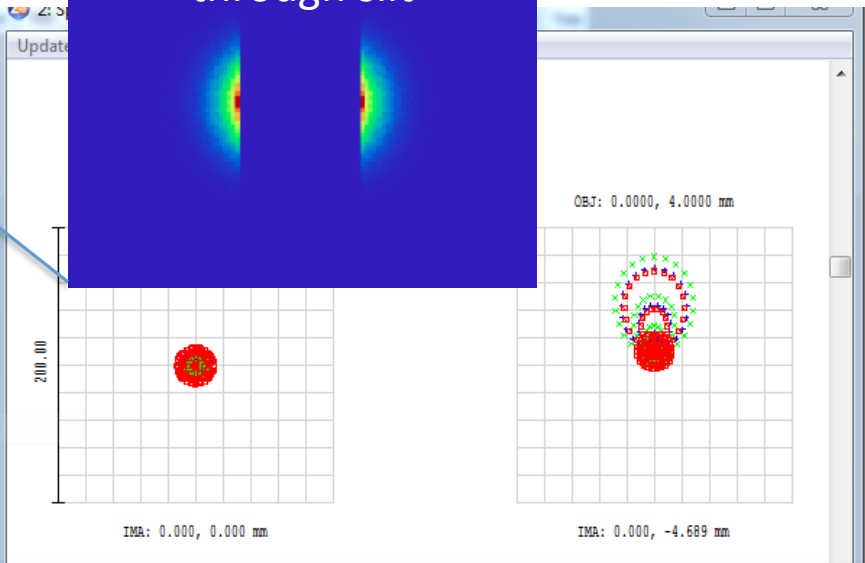
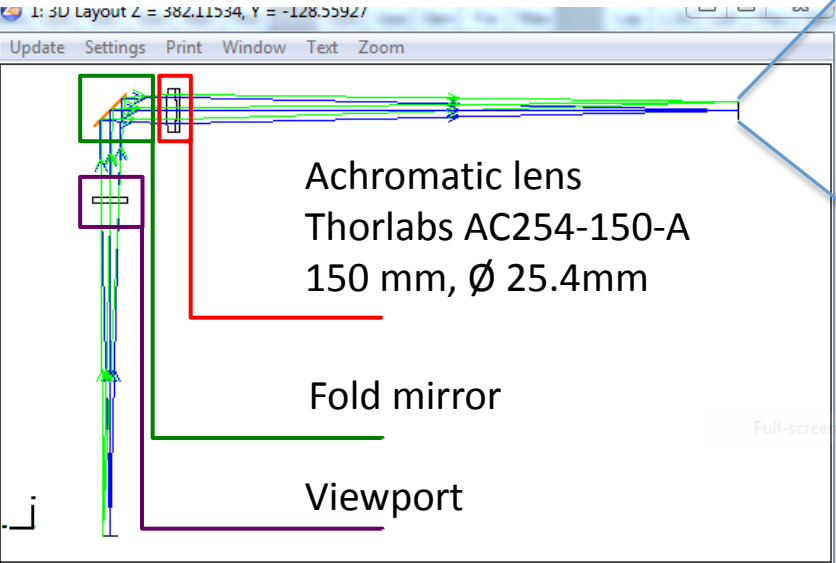
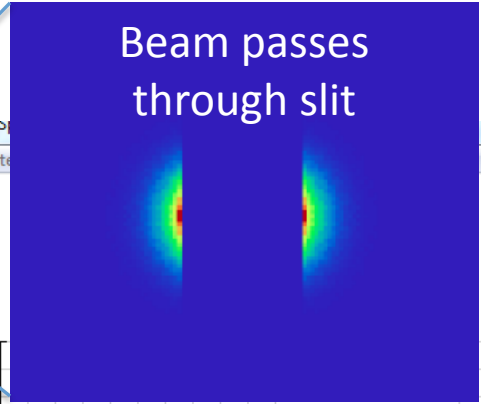
	E (GeV)	σ_H (μm)	σ_V (μm)
CesrTA	2.1	320	~ 9.2
	5.3	2500	~ 65



D. Rubin et al., "CesrTA Layout and Optics", Proc. of PAC2009, Vancouver, Canada, WE6PFP103, p. 2751.

<http://www.cs.cornell.edu>

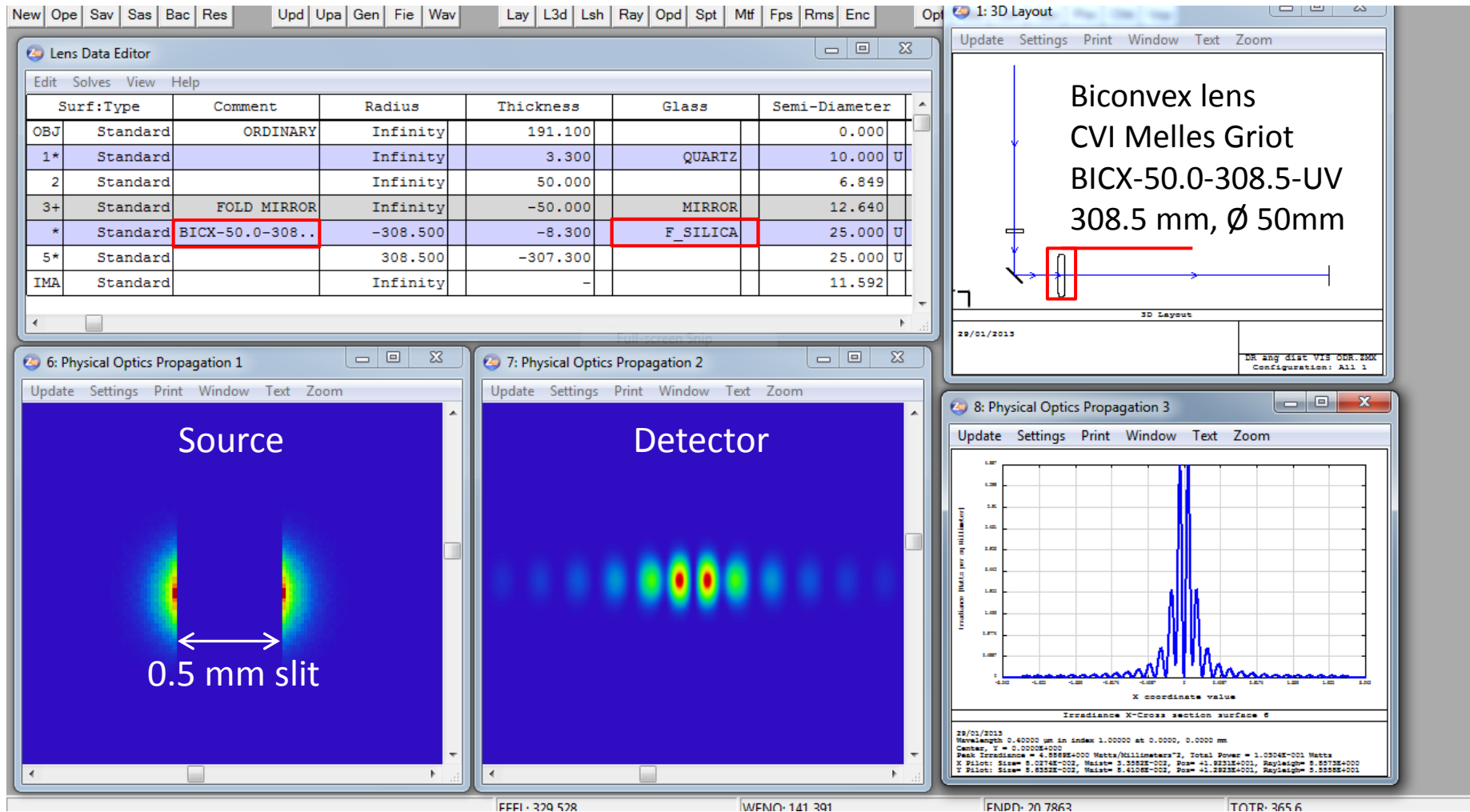
Simulations - Imaging the slit



Lens Data Editor

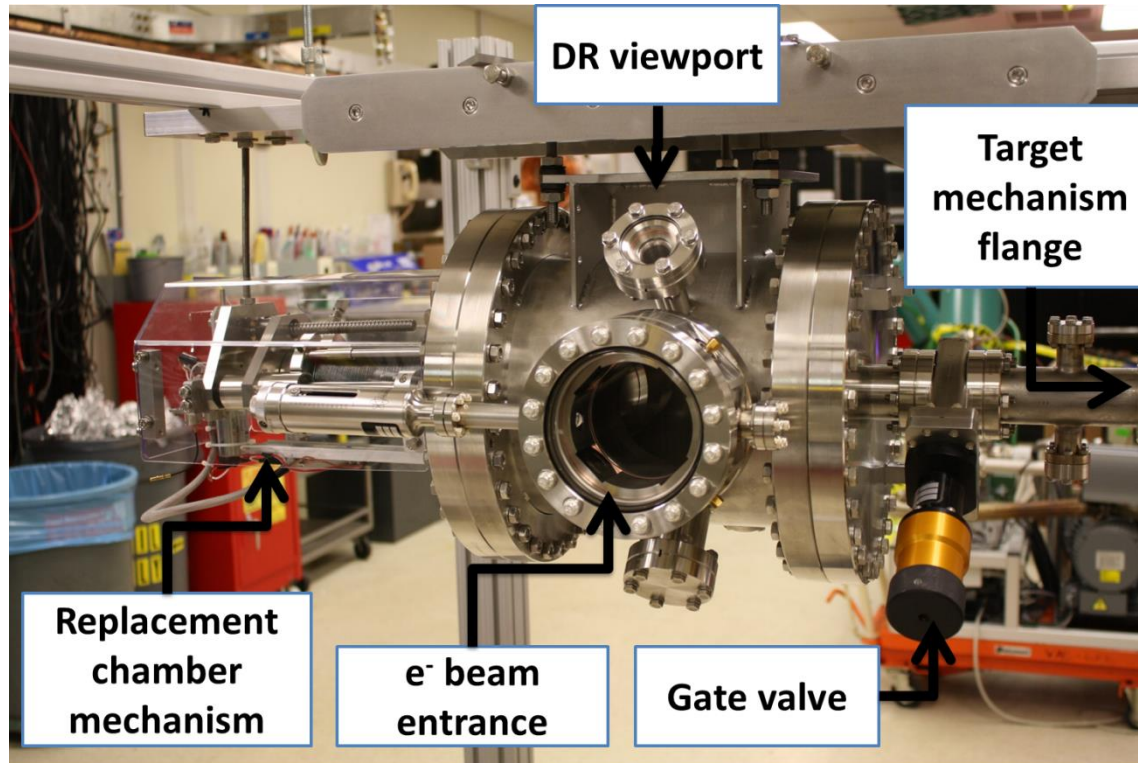
Surf	Type	Comment	Radius	Thickness	Glass	Semi-Diameter	Par 1 (unused)	Par 2 (unused)	Par 3 (unused)
OBJ	Standard		Infinity	191.900		4.000			
*	Standard		Infinity	3.300	QUARTZ	10.000			
2	Standard		Infinity	50.000		7.100			
3	Coordinat..	-45	0.000	0.000	-	0.000	0.000	0.000	-45.000
4	Standard	FOLD MIRROR	Infinity	0.000	MIRROR	13.047			
5	Coordinat..	-45	0.000	-32.220	-	0.000	0.000	0.000	-45.000
6*	Standard	AC254-150-A	-91.620	-5.700	N-BK7	12.700			
7*	Standard		66.680	-2.200	SF5	12.700			
8*	Standard		197.700	0.000		12.700			
9	Standard		Infinity	-321.295		10.988			
IMA	Standard		Infinity	-		4.680			

Simulating DR from a single electron – real lens



ODR angular distribution is very sensitive to distances away from the focal plane. The detector must therefore be exactly in the back focal plane.

Vacuum chamber assembly

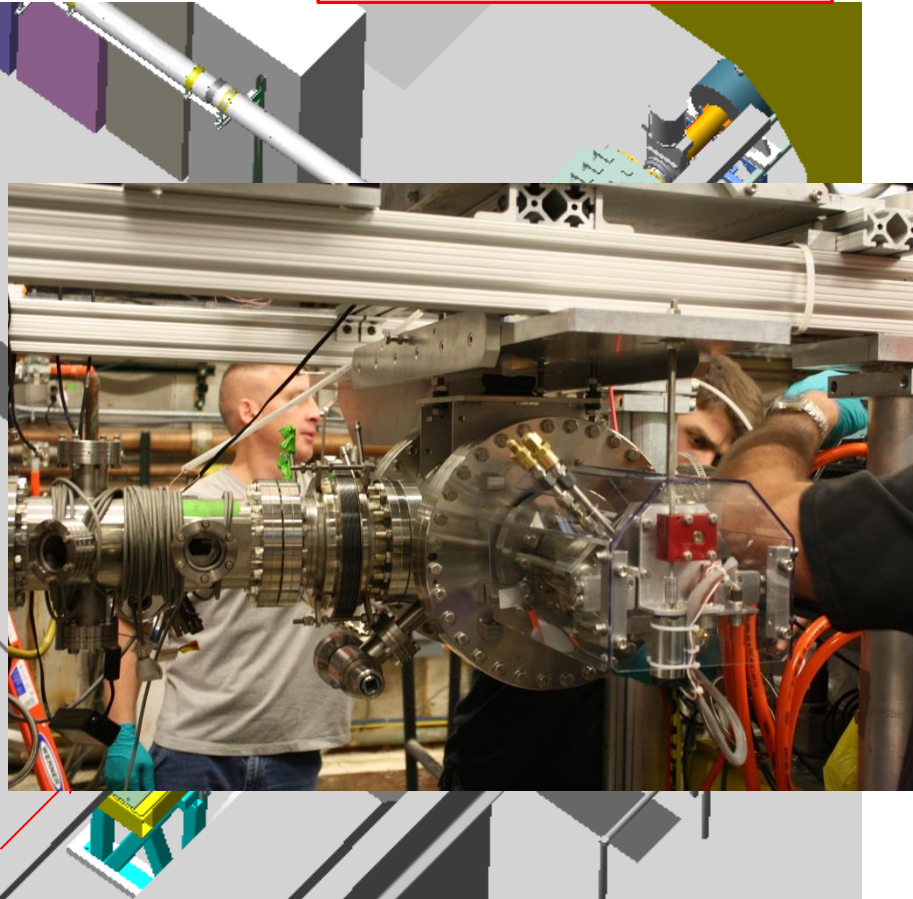
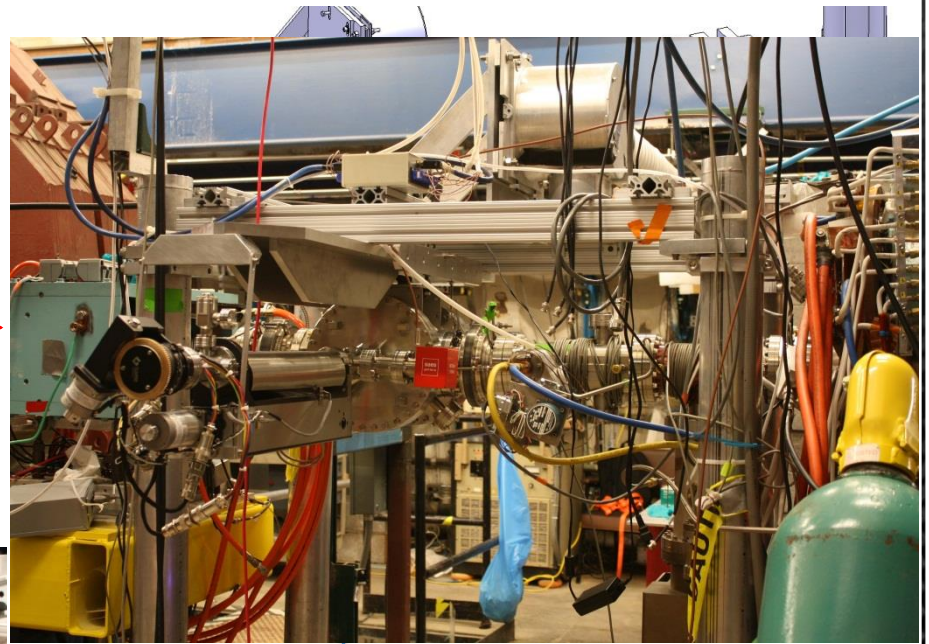


- LHS : CHES operation
- RHS: DR experiment
- Optical system connected to DR viewport
- Gate valve to disconnect CESR vacuum for target changeover
- Target mechanism: rotation + translation IN/OUT

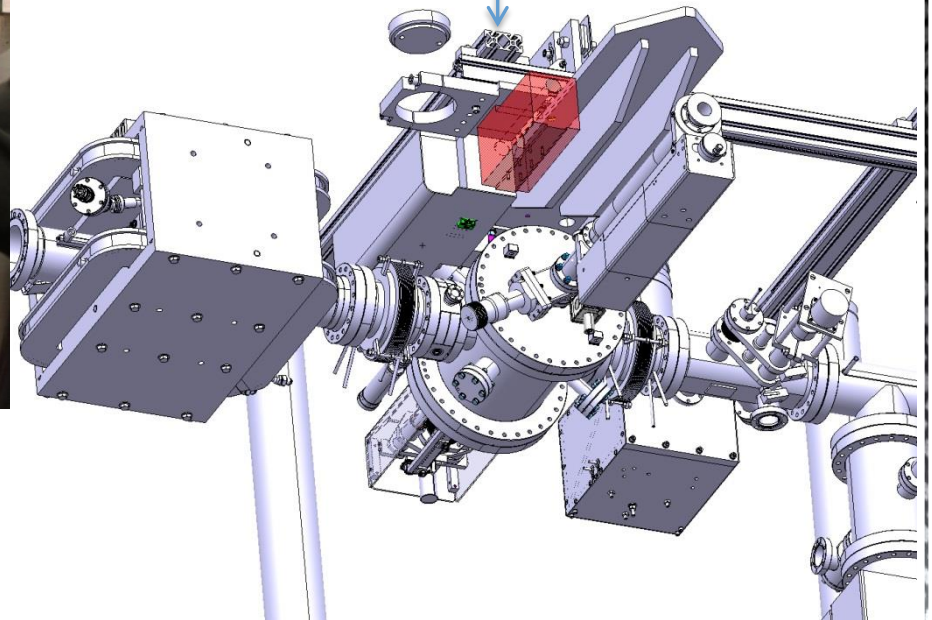
LHS = Left Hand Side
RHS = Right Hand Side

L3 layout @CesrTA

Electron beam direction →



DR experiment

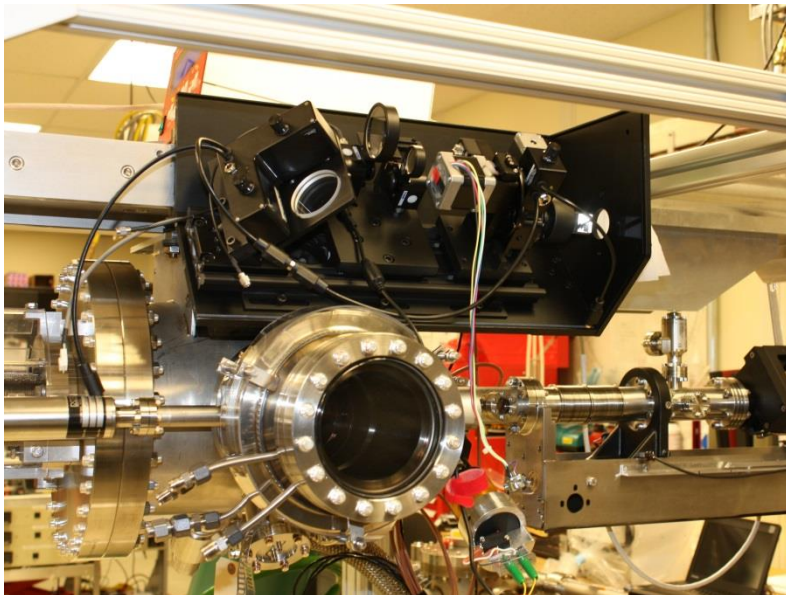
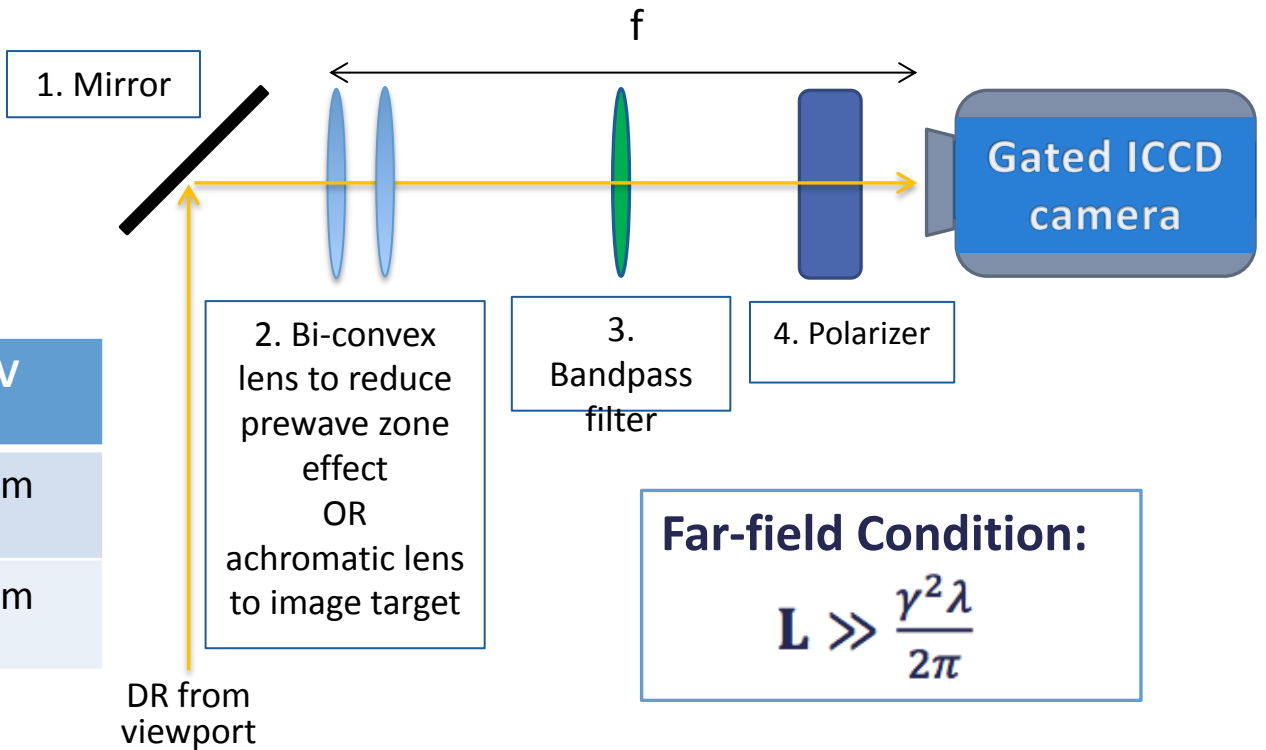


Technical drawings by N. Chritin

Optical System

$$\frac{g^2 l}{2\rho} \text{ given } \gamma \text{ and } \lambda:$$

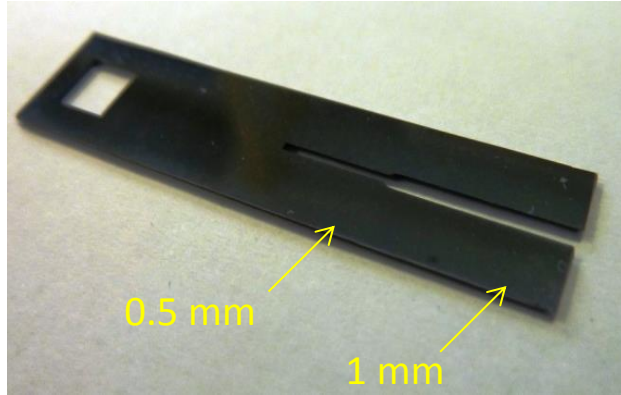
	2.1 GeV	5 GeV
200 nm	0.54 m	3.18 m
400 nm	1.08 m	6.37 m



- L = distance from source of DR to detector
- Compact optical system is in the prewave zone therefore a biconvex lens is used with detector in back focal plane to obtain the angular distribution.

(Pre-wave zone effect in transition and diffraction radiation: Problems and Solutions -P. V. Karataev).

Target



Chemical etching:

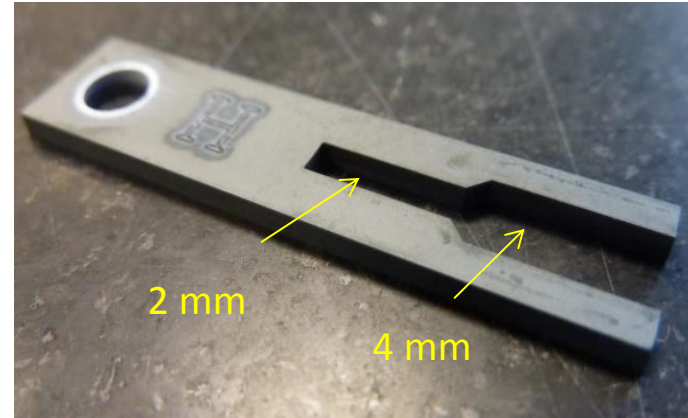
Silicon wafers are dipped into etchant (e.g. acidic mixture)



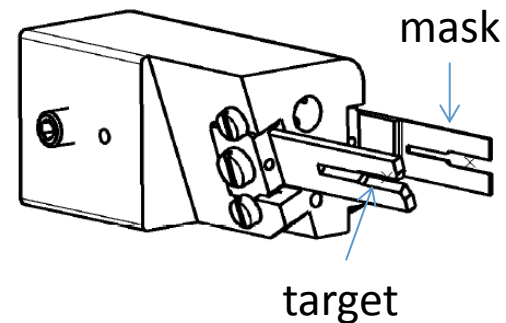
Molecular adhesion:

Two substrates with perfectly flat surfaces (e.g. polished mirror surfaces) adhere to one another, without adhesive (e.g. glue)

Mask

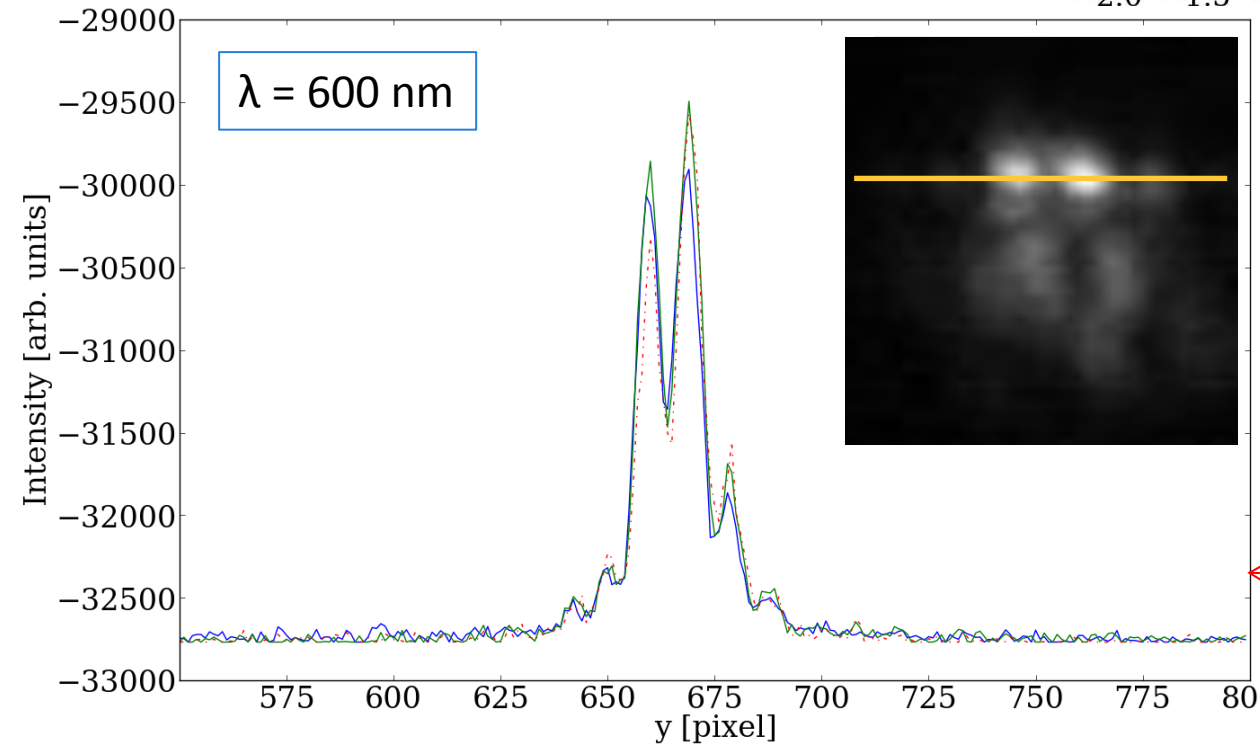
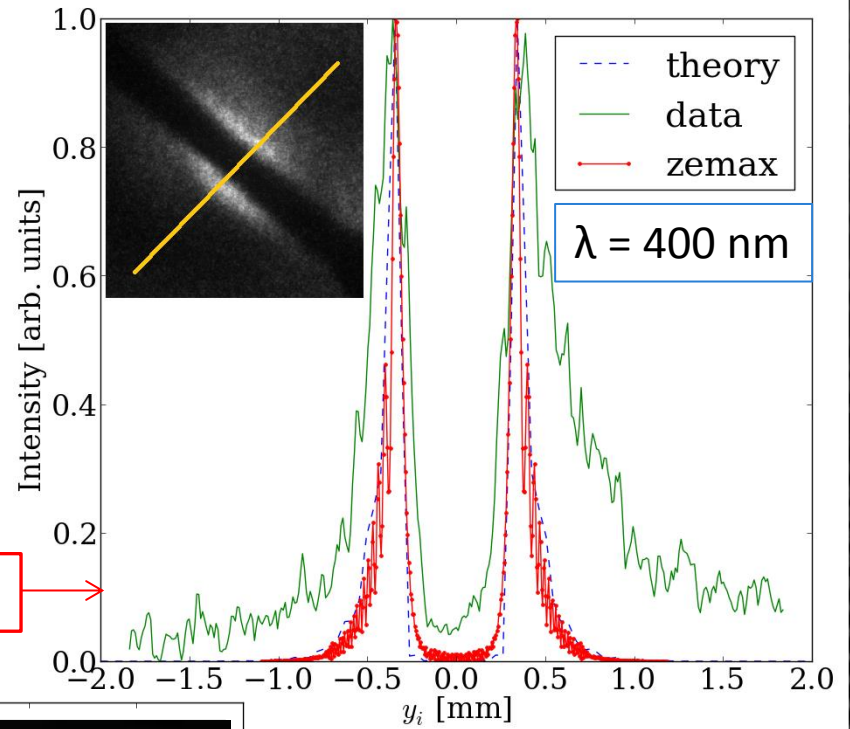


- Silicon Carbide
- **Laser machining**
- Not etched (orientated perpendicular to beam)



Example images

- 2.1 GeV
- 1 mm slit aperture
- 1 mA single- bunch beam



Theory-
D. Xiang et al., Phys.
Rev. ST Accel. Beams,
10 (2007) 062801.

Zemax-
T. Aumeyr et al.,
IBIC2013, WEPF18.

OTR/ODR emittance station – proposed time table

- **Keep OTR/LW location:**
 - Beam optics verified and well understood
 - Beam size, flexibility and tunability known
 - Transversal beam size resolution still not good enough → replace existing vacuum chamber
- Attach currently used BPM to new chamber
- **Schedule:**
 - 0.5 years: simulation of the current system (capabilities, possible improvements) → potential experimental tests
 - 1 year: Design and simulation of new system. Installation: 09/2015 (till the end of the summer 2015 shutdown)
 - 1.5 years: Experimental tests from 10/2015 till 06/2017 (~ **2 operational years**).

Shift request

- **Year 1:**

- **5 shifts:** Commissioning and observation of OTR/ODR angular distributions (initial tests < 400 nm)
- **5 shifts:** Resolution optimisation of the OTR/ODR and demonstration of high-resolution beam size measurements
- **5 shifts:** Beam dynamics studies (incl. quad scan and beam roll angle)

- **Year 2:**

- During Year 1: analysis of the experimental conditions and design short wavelength measurement system (< 200 nm)
- Summer 2016 shutdown: upgrade of optical system
- Year 2 → demonstrate performance of short wavelength measurement. **Repeat the measurements** performed in the optical wavelength range for comparison

Thank you for your attention!

